

Title (en)
SURVEY SYSTEM

Title (de)
VERMESSUNGSSYSTEM

Title (fr)
SYSTÈME D'INSPECTION

Publication
EP 3258290 B1 20210825 (EN)

Application
EP 17175616 A 20170613

Priority
JP 2016117721 A 20160614

Abstract (en)
[origin: EP3258290A1] Provided is a survey system capable of acquiring point group data of a three-dimensional object desired to be measured without complicated setting. A survey system (1) includes a surveying instrument (2) including a tracking section that tracks a target by emitting tracking light and receiving the tracking light reflected on the target (9), and a scanner (22) that rotates horizontally and integrally with the surveying instrument and performs scanning around a single axis in a vertical direction, and the scanner and the tracking section are offset in the horizontal direction. Therefore, a scanning line (SL) does not match the target, and is always controlled around the target.

IPC 8 full level
G01S 17/42 (2006.01); **G01C 15/00** (2006.01); **G01S 17/66** (2006.01); **G01S 17/87** (2020.01); **G01S 17/89** (2020.01)

CPC (source: EP US)
G01C 3/04 (2013.01 - US); **G01C 15/002** (2013.01 - EP US); **G01S 17/42** (2013.01 - EP US); **G01S 17/66** (2013.01 - EP US);
G01S 17/87 (2013.01 - EP US); **G01S 17/89** (2013.01 - EP US)

Designated contracting state (EPC)
AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

DOCDB simple family (publication)
EP 3258290 A1 20171220; EP 3258290 B1 20210825; JP 2017223489 A 20171221; JP 6713847 B2 20200624; US 10591290 B2 20200317;
US 2017356741 A1 20171214

DOCDB simple family (application)
EP 17175616 A 20170613; JP 2016117721 A 20160614; US 201715619079 A 20170609